

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	("438"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:09
L2	0	("438"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
L3	0	(semiconductor with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
L4	0	("257"/\$.ccls. with (flip adj chip)) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:08
L5	1	(flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:10
L6	28881	(flip adj chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:11
L7	2	(flip adj chip) and ((test\$6 adj pad) with peripheral) and (bond\$5 adj pad) and ((trace or conductive) adj line) and @ad<="20030528"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:10
L8	44	6 and ((test\$4 adj pad) with peripheral)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:12

L9	38	8 and (bond\$5 adj pad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:12
L10	3	9 and ((trace or conductive) adj line)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:13
L11	5	("6674159") or ("6803659").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/20 14:32
L12	39	(micron.as.) and (test adj probe) and (flip adj chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/20 14:32
S1	2164	(257/778).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/05 10:26
S6	375	257/778.ccls. and (flip adj chip) and pad and test\$6 and @ad<="20030528"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/05 10:38
S7	297	257/778.ccls. and (flip adj chip) and pad and test\$6 and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:53
S12	6	("5132757") or ("5766969") or ("6083846") or ("6127212") or ("6258680") or ("20040173794").PN.	US-PGPUB; USPAT	OR	OFF	2004/12/13 11:05
S13	2	257/778.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:54
S14	26	"257"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 09:48

S15	0	("257"/\$.ccls. with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:55
S16	0	(semiconductor with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2004/12/13 08:55
S17	0	("438"/\$.ccls. with (flip adj chip) with pad with (test\$6 adj pad) with (trace adj line)) and @ad<="20030528"	USPAT	OR	ON	2005/10/20 14:05
S18	26	"257"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S19	12	"438"/\$.ccls. and (flip adj chip) and pad and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S20	0	"438"/\$.ccls. and (flip adj chip adj pad) and test\$6 and (trace adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:03
S21	0	"438"/\$.ccls. and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:04
S22	4	"257"/\$.ccls. and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:05
S23	4	semiconductor and (flip adj chip adj pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:04
S24	0	("257"/\$.ccls. with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S25	0	("438"/\$.ccls. with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S26	10	(semiconductor with (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
S27	0	(semiconductor near (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06

S28	11	(semiconductor same (flip adj chip)) and (pad) and (test\$6 adj pad) and (conductive adj line) and @ad<="20030528"	USPAT	OR	ON	2005/05/12 10:06
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